

Notice of References Cited	Application/Control No. 10/729,332		Applicant(s)/Patent Under Reexamination KWAK ET AL.	
	Examiner SIMON D NGUYEN		Art Unit 2685	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0097623	05-2003	Razavilar et al.	714/704
	B	US-2003/0223354	12-2003	Olszewski, Kim Joseph	370/208
	C	US-6,850,736	02-2005	McCune, Jr., Earl W.	455/67.13
	D	US-2002/0102944	08-2002	Haim, John W.	455/70
	E	US-6,654,613	11-2003	Maeng et al.	455/522
	F	US-2002/0018453	02-2002	Yu et al.	370/333
	G	US-2003/0045243	03-2003	RAUHALA, ANTTI	455/67.3
	H	US-6,871,066	03-2005	Khullar et al.	455/423
	I	US-6,108,374	08-2000	Balachandran et al.	375/227
	J	US-6,456,652	09-2002	Kim et al.	375/224
	K	US-6,535,733	03-2003	Matusevich et al.	455/424
	L	US-6,201,954	03-2001	Soliman, Samir S.	455/226.2
	M	US-6,229,848	05-2001	Tanaka, Hiroshi	375/227

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.